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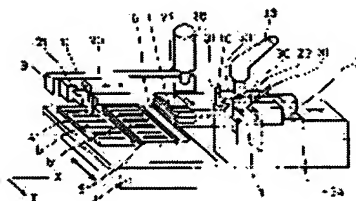
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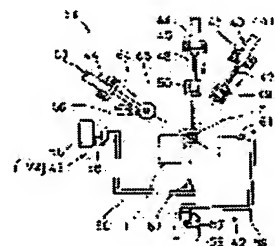
(54) CHARACTERISTIC MEASURING DEVICE

(57)Abstract:

PURPOSE: To automate measuring processes of electric and optical characteristics and select the characteristics at high speed with high accuracy by measuring LD bar-like elements of respective semiconductor laser parts in strip bodies in such a manner that respective optical sensors move alternately.



CONSTITUTION: A detection mechanism 34 (40-44) makes optical sensors 61 and 62 face on measured points alternately every each time a stage 1 performs a slide movement and then its mechanism detects output characteristics, far field patterns, and peak frequencies of a semiconductor laser. Consequently, in a single semiconductor laser part, the mechanism is allowed to perform characteristic checks of desired items by bringing once a probe needle 30 into contact with the laser part. This approach not only improves the working efficiency but also lessens possibilities of giving rise to any damage to the semiconductor laser part due to contact which is just made between its laser part and the probe needle. In this way, the semiconductor laser part causes monolithic strips 8 that are arranged in parallel to be used as



samples; besides, respective characteristics of each semiconductor laser part are measured and selected.

LEGAL STATUS

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